2SB1679G

Silicon PNP epitaxial planar type

For low-frequency amplification

■ Features

- \bullet Large collector output capacitance (Common base, input open circuited) C_{ob}
- ullet Low collector-emitter saturation voltage $V_{\text{CE(sat)}}$
- S-Mini type package, allowing downsizing of the equipment and automatic insertion through the tape packing

■ Absolute Maximum Ratings $T_a = 25^{\circ}C$

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V_{CBO}	-15	V	
Collector-emitter voltage (Base open)	V_{CEO}	-10	V	
Emitter-base voltage (Collector open)	V _{EBO}	-7	V	
Collector current	I_{C}	- 0.5	A	
Peak collector current	I_{CP}	-1	A	
Collector power dissipation	P _C	150	mW	
Junction temperature	T _j	150	°C	
Storage temperature	T _{stg}	-55 to +150	°C	

Package

- Code SMini3-F2
- Marking Symbol: 3V
- Pin Name
 - 1. Base
 - 2. Emitter
 - 3. Collector

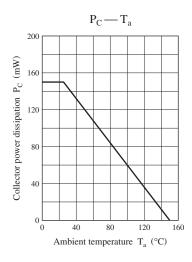
■ Electrical Characteristics $T_a = 25$ °C ± 3°C

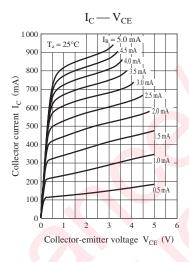
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V _{CBO}	$I_C = -10 \mu\text{A}, I_E = 0$	-15	5		V
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = -1 \text{ mA}, I_B = 0$	-10	,0		V
Emitter-base voltage (Collector open)	V_{EBO}	$I_E = -10 \mu A, I_C = 0$	-7			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = -10 \text{ V}, I_E = 0$			-100	nA
Forward current transfer ratio *1	h _{FE1} *2	$V_{CE} = -2 \text{ V}, I_{C} = -0.5 \text{ A}$	130		350	_
	h _{FE2}	$V_{CE} = -2 \text{ V}, I_{C} = -1 \text{ A}$	60			
Collector-emitter saturation voltage *1	V _{CE(sat)}	$I_C = -0.4 \text{ A}, I_B = -8 \text{ mA}$		- 0.16	- 0.30	V
Base-emitter saturation voltage *1	V _{BE(sat)}	$I_C = -0.4 \text{ A}, I_B = -8 \text{ mA}$		- 0.8	-1.2	V
Transition frequency	f_T	$V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		130		MHz
Collector output capacitance (Common base, input open circuited)	C _{ob}	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		22		pF

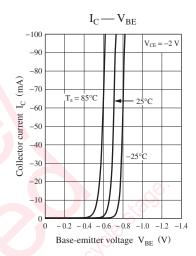
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

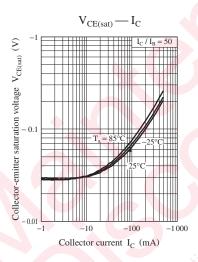
- 2. *1: Pulse measurement
 - *2: Rank classification

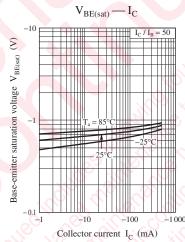
Rank	R	S
$h_{\rm FE1}$	130 to 220	180 to 350

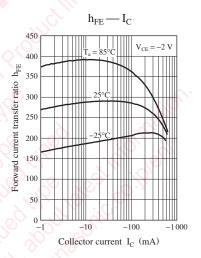




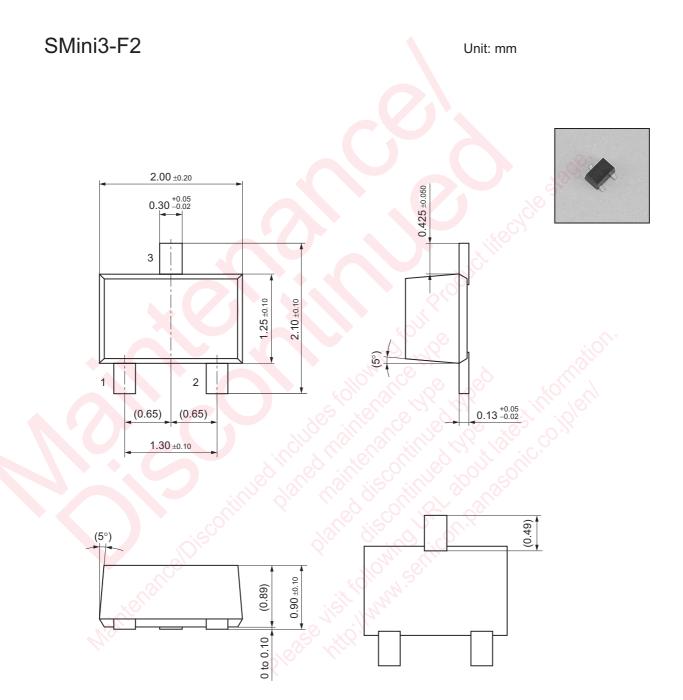








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